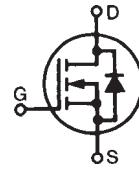


High Voltage Power MOSFET

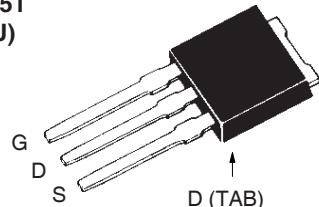
IXTU05N100
IXTY05N100

V_{DSS} = 1000V
I_{D25} = 750mA
R_{DS(on)} ≤ 17Ω

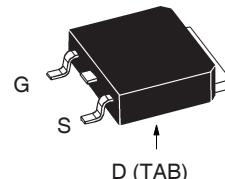
N-Channel Enhancement Mode
Avalanche Rated



TO-251
(IXTU)



TO-252
(IXTY)



G = Gate D = Drain
S = Source TAB = Drain

Symbol	Test Conditions	Maximum Ratings	
V _{DSS}	T _J = 25°C to 150°C	1000	V
V _{DGR}	T _J = 25°C to 150°C, R _{GS} = 1MΩ	1000	V
V _{GSS}	Continuous	±30	V
V _{GSM}	Transient	±40	V
I _{D25}	T _C = 25°C	750	mA
I _{DM}	T _C = 25°C, Pulse Width Limited by T _{JM}	3	A
I _A	T _C = 25°C	1	A
E _{AS}	T _C = 25°C	100	mJ
dv/dt	I _S ≤ I _{DM} , V _{DD} ≤ V _{DSS} , T _J = 150°C	3	V/ns
P _D	T _C = 25°C	40	W
T _J		-55 ... +150	°C
T _{JM}		150	°C
T _{stg}		-55 ... +150	°C
T _L	Maximum Lead Temperature for Soldering	300	°C
T _{SOLD}	1.6 mm (0.062in.) from Case for 10s	260	°C
F _c	Mounting force	1.13 / 10	Nm/lb.in.
Weight	TO-251	0.40	g
	TO-252	0.35	g

Symbol	Test Conditions (T _J = 25°C, Unless Otherwise Specified)	Characteristic Values		
		Min.	Typ.	Max.
BV _{DSS}	V _{GS} = 0V, I _D = 250μA	1000		V
V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250μA	2.5		V
I _{GSS}	V _{GS} = ± 30V, V _{DS} = 0V		±100 nA	
I _{DSS}	V _{DS} = V _{DSS} , V _{GS} = 0V T _J = 125°C		25 μA 500 μA	
R _{DS(on)}	V _{GS} = 10V, I _D = 375mA, Note 1		17 Ω	

Features

- International Standard Packages
- Fast Switching Times
- Avalanche Rated
- R_{ds(on)} HDMOS™ Process
- Rugged Polysilicon Gate Cell structure
- Extended FBSOA

Advantages

- High Power Density
- Space Savings

Applications

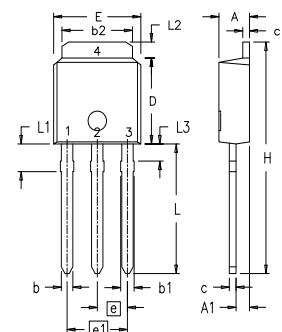
- Switch-Mode and Resonant-Mode Power Supplies
- Flyback Inverters
- DC Choppers

Symbol	Test Conditions ($T_J = 25^\circ\text{C}$, Unless Otherwise Specified)	Characteristic Values		
		Min.	Typ.	Max.
g_{fs}	$V_{DS} = 20\text{V}$, $I_D = 500\text{mA}$, Note 1	0.55	0.93	S
C_{iss} C_{oss} C_{rss}	$V_{GS} = 0\text{V}$, $V_{DS} = 25\text{V}$, $f = 1\text{MHz}$	260	pF	
		22	pF	
		8	pF	
$t_{d(on)}$ t_r $t_{d(off)}$ t_f	Resistive Switching Times $V_{GS} = 10\text{V}$, $V_{DS} = 0.5 \cdot V_{DSS}$, $I_D = 1\text{A}$ $R_G = 47\Omega$ (External)	11	ns	
		19	ns	
		40	ns	
		28	ns	
$Q_{g(on)}$ Q_{gs} Q_{gd}	$V_{GS} = 10\text{V}$, $V_{DS} = 0.5 \cdot V_{DSS}$, $I_D = 1\text{A}$	7.8	nC	
		1.4	nC	
		4.1	nC	
R_{thJC}			3.1 $^\circ\text{C}/\text{W}$	

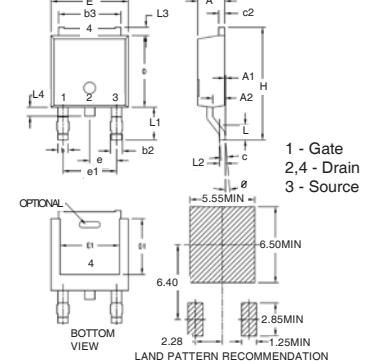
Source-Drain Diode

Symbol	Test Conditions ($T_J = 25^\circ\text{C}$, Unless Otherwise Specified)	Characteristic Values		
		Min.	Typ.	Max.
I_s	$V_{GS} = 0\text{V}$		750 mA	
I_{SM}	Repetitive, Pulse Width Limited by T_{JM}		3 A	
V_{SD}	$I_F = I_S$, $V_{GS} = 0\text{V}$, Note 1		1.5 V	
t_{rr}	$I_F = I_S$, $-di/dt = 100\text{A}/\mu\text{s}$ $V_R = 100\text{V}$, $V_{GS} = 0\text{V}$	710	ns	

Note 1: Pulse test, $t \leq 300\mu\text{s}$, duty cycle, $d \leq 2\%$.

TO-251 Outline

1. Gate
3. Source
2. Drain
4. Drain

Dim.	Millimeter		Inches	
	Min.	Max.	Min.	Max.
A	2.19	2.38	.086	.094
A1	0.89	1.14	.035	.045
b	0.64	0.89	.025	.035
b1	0.76	1.14	.030	.045
b2	5.21	5.46	.205	.215
c	0.46	0.58	.018	.023
c1	0.46	0.58	.018	.023
D	5.97	6.22	.235	.245
E	6.95	6.73	.250	.265
e	2.28	BSC	.090	BSC
e1	4.57	BSC	.180	BSC
H	17.02	17.78	.670	.700
L	8.89	9.65	.350	.380
L1	1.91	2.28	.075	.090
L2	0.89	1.27	.035	.050

TO-252 AA Outline

1 - Gate
2,4 - Drain
3 - Source

SYM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.086	.094	.219	.238
A1	0	.005	0	.012
A2	.038	.046	.097	.117
b	.025	.035	.064	.089
b2	.030	.045	.076	.114
b3	.200	.215	.508	.546
c	.018	.024	.046	.061
c2	.018	.023	.046	.058
D	.235	.245	.597	.622
D1	.180	.205	.457	.521
E	.250	.265	.635	.673
E1	.170	.205	.432	.521
e	.090 BSC		.228 BSC	
e1	.180 BSC		.457 BSC	
H	.370	.410	.940	10.42
L	.055	.070	.140	.178
L1	.100	.115	.254	.292
L2	.020 BSC		.050 BSC	
L3	.025	.040	.064	.102
L4	.025	.040	.064	.102
θ	0°	10°	0°	10°

IXYS Reserves the Right to Change Limits, Test Conditions, and Dimensions.

IXYS MOSFETs and IGBTs are covered by one or more of the following U.S. patents: 4,835,592, 4,931,844, 5,049,961, 5,237,481, 6,162,665, 6,404,065 B1, 6,683,344, 6,727,585, 7,005,734 B2, 7,157,338B2, 4,860,072, 5,017,508, 5,063,307, 5,381,025, 6,259,123 B1, 6,534,343, 6,710,405 B2, 6,759,692, 7,063,975 B2, 4,881,106, 5,034,796, 5,187,117, 5,486,715, 6,306,728 B1, 6,583,505, 6,710,463, 6,771,478 B2, 7,071,537

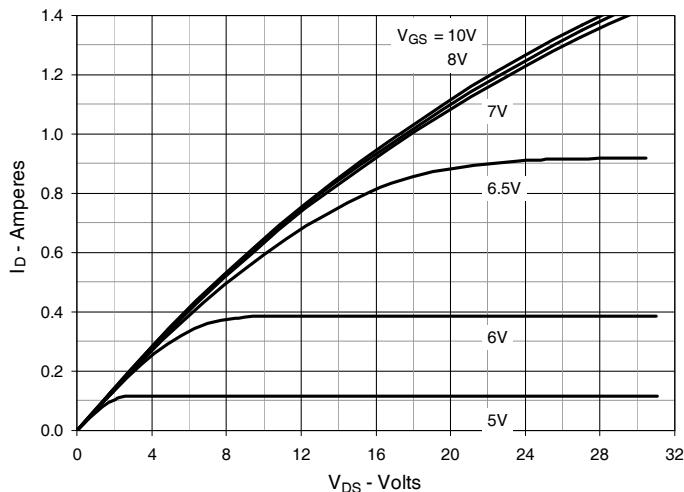
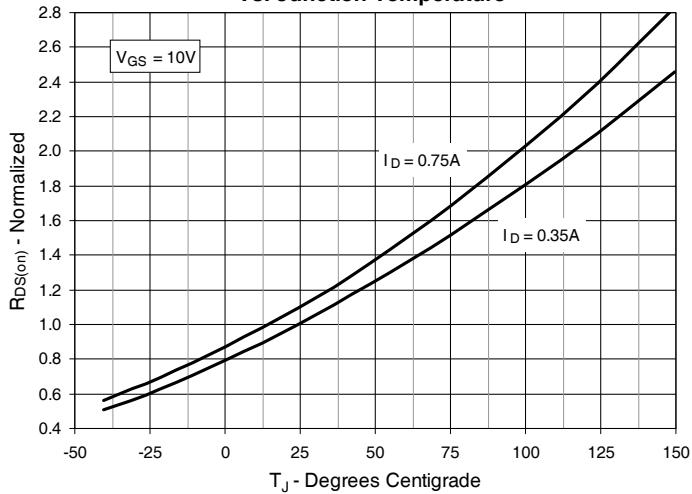
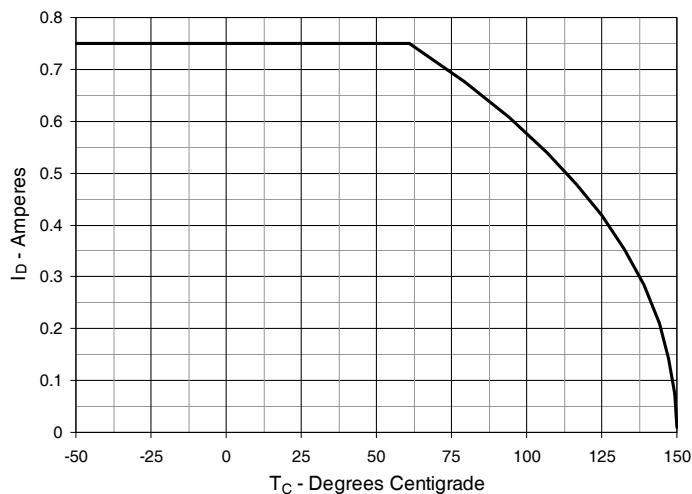
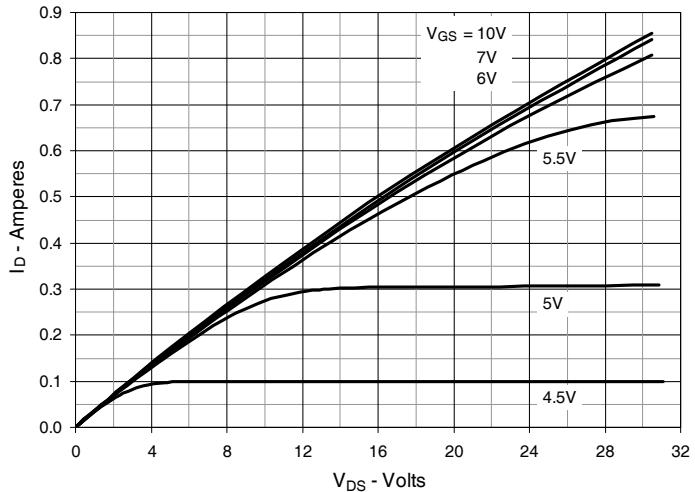
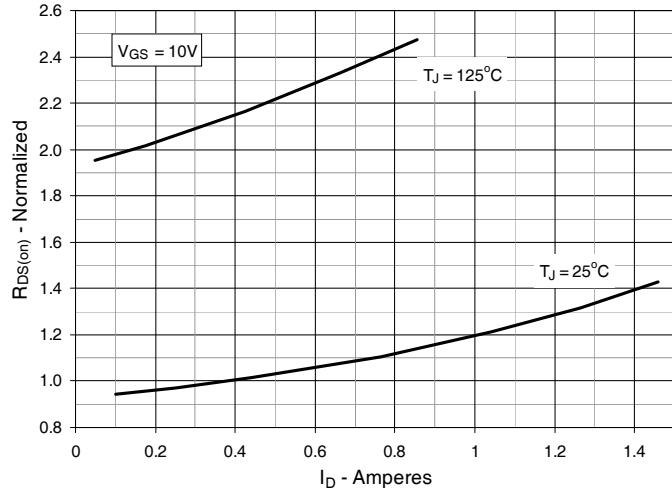
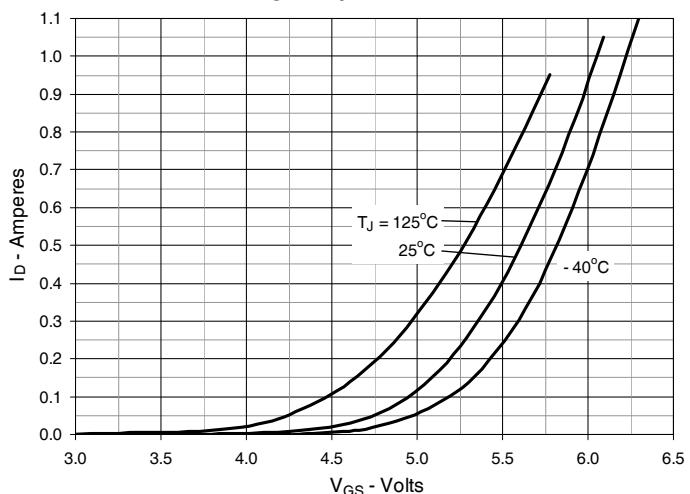
Fig. 1. Output Characteristics @ $T_J = 25^\circ\text{C}$

Fig. 3. $R_{DS(on)}$ Normalized to $I_D = 0.35\text{A}$ Value vs. Junction Temperature

Fig. 5. Maximum Drain Current vs. Case Temperature

Fig. 2. Output Characteristics @ $T_J = 125^\circ\text{C}$

Fig. 4. $R_{DS(on)}$ Normalized to $I_D = 0.35\text{A}$ Value vs. Drain Current

Fig. 6. Input Admittance


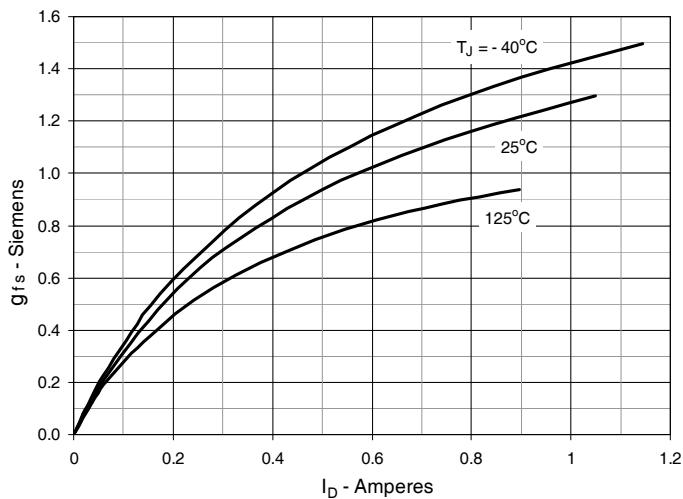
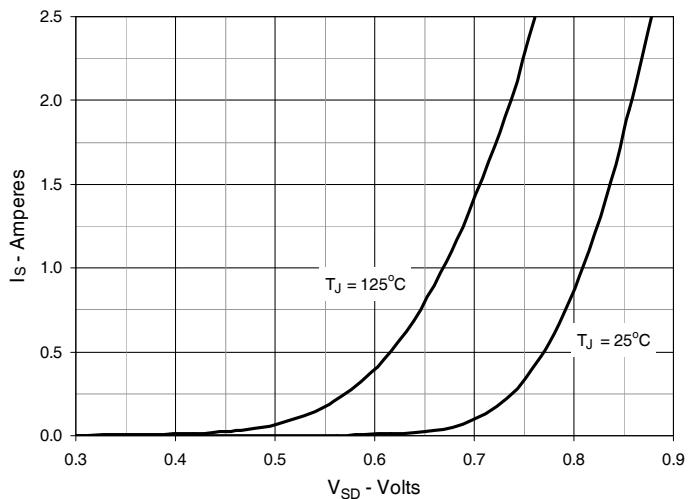
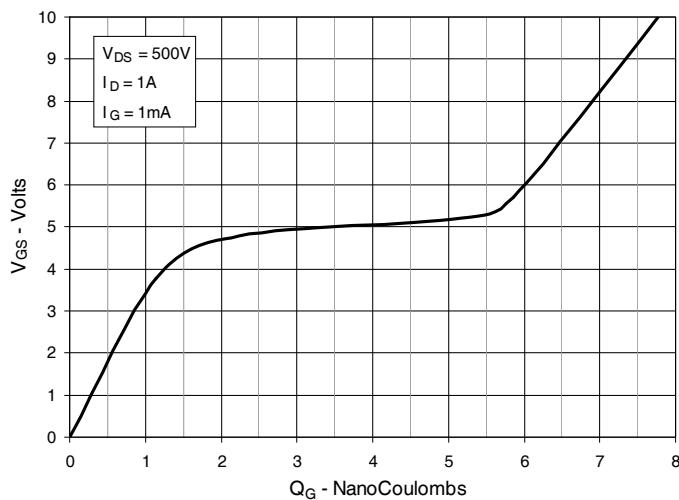
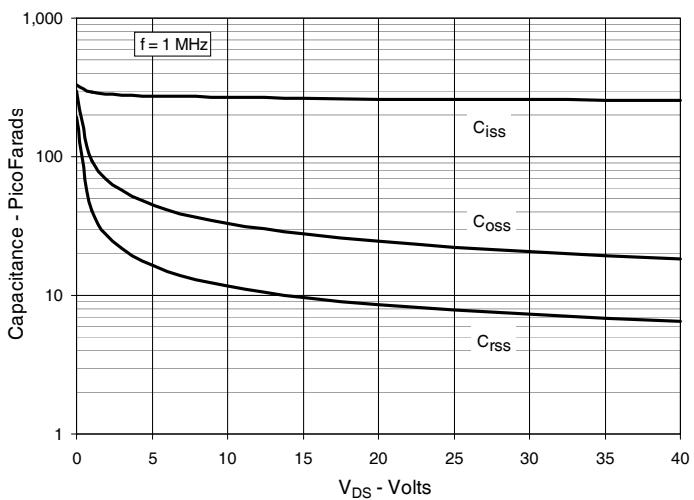
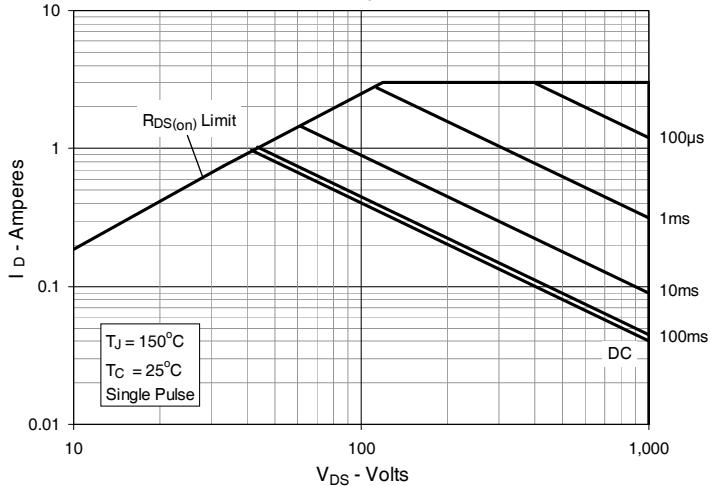
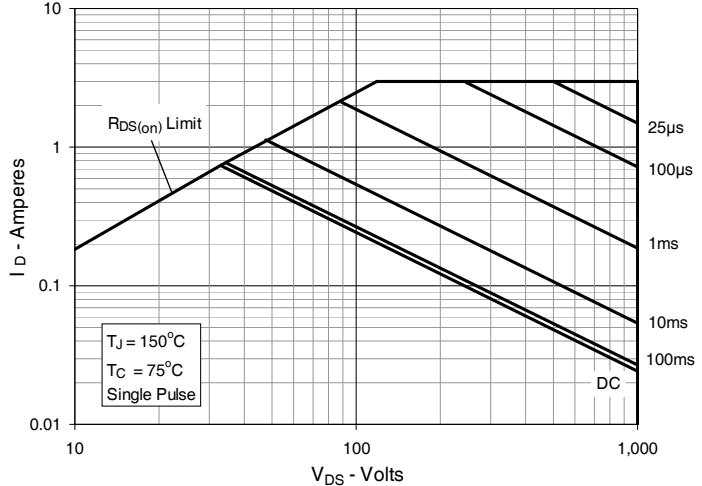
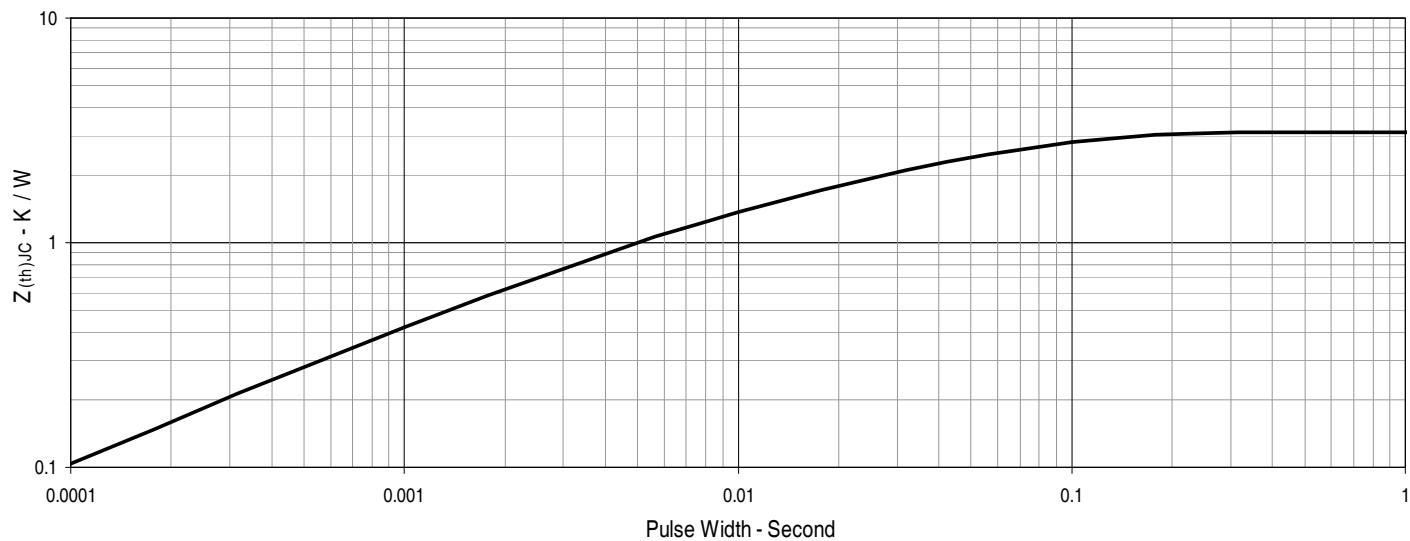
Fig. 7. Transconductance

Fig. 8. Forward Voltage Drop of Intrinsic Diode

Fig. 9. Gate Charge

Fig. 10. Capacitance

**Fig. 11. Forward-Bias Safe Operating Area
@ $T_C = 25^\circ\text{C}$**

**Fig. 12. Forward-Bias Safe Operating Area
@ $T_C = 75^\circ\text{C}$**


Fig. 13. Maximum Transient Thermal Impedance





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